
Surface chemical analysis — Total reflection X-ray fluorescence analysis of water

Analyse chimique des surfaces — Analyse par fluorescence de rayons X en réflexion totale d'eau

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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	2
4 Symbols and abbreviated terms	3
5 Safety	3
6 Interferences	3
7 Apparatus	3
7.1 General	3
7.2 Labware	4
7.3 Drying apparatus	4
8 Reagents, standards and materials	4
9 Sample preparation	5
9.1 Environment	5
9.2 Sample	5
9.3 Specimen	6
9.4 Sample carrier	6
9.5 Trials/replicates	6
9.6 Effect of residue mass, size and its position	7
10 Procedure	7
10.1 General	7
10.2 Instrument calibration	7
10.3 Detection limit	7
10.4 TXRF measurements	8
10.5 Spectra fitting	8
10.6 Unknown samples	8
11 Qualitative and quantitative analysis	8
11.1 Identification of elements	8
11.2 Quantification of elements	8
11.3 Calculations	9
11.4 Measurement uncertainty	9
12 Quality control	9
13 Precision and accuracy	10
14 Test report	10
Annex A (informative) Uncertainty in TXRF measurements	11
Annex B (informative) Validation of the method	15
Bibliography	19

Foreword

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